


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574455	<b>Applicant(s)/Patent Under Reexamination</b>  NIV ET AL.
	<b>Examiner</b>  BENJAMIN P LEE	<b>Art Unit</b>  3641

SEARCHED			
Class	Subclass	Date	Examiner
89	40.03	10/16/2008	LEE
89	37.17	10/16/2008	LEE
89	41.02	10/16/2008	LEE
89	41.05	10/16/2008	LEE
89	36.08	10/16/2008	LEE

SEARCH NOTES		
Search Notes	Date	Examiner
Text search	10/16/2008	LEE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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